

March 2007

# **FDS8817NZ**

# N-Channel PowerTrench<sup>®</sup> MOSFET 30V, 15A, 7.0m $\Omega$

#### **Features**

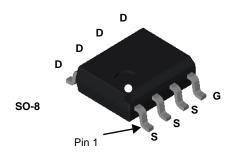
- Max  $r_{DS(on)} = 7m\Omega$  at  $V_{GS} = 10V$ ,  $I_D = 15A$
- Max  $r_{DS(on)}$  = 10m $\Omega$  at  $V_{GS}$  = 4.5V,  $I_D$  =12.6A
- HBM ESD protection level of 3.8kV typical (note 3)
- High performance trench technology for extremely low r<sub>DS(on)</sub>
- High power and current handling capability
- RoHS compliant

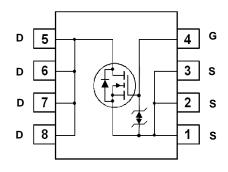


This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench® process that has been especially tailored to minimize the on-state resistance.

This device is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.







# **MOSFET Maximum Ratings** $T_A = 25$ °C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DS</sub>	Drain to Source Voltage		30	V
V <sub>GS</sub>	Gate to Source Voltage		±20	V
1	Drain Current -Continuous	(Note 1a)	15	^
ID.	-Pulsed		60	Α
E <sub>AS</sub>	Single Pulse Avalanche Energy	(Note 4)	181	mJ
Б	Power Dissipation	(Note 1a)	2.5	10/
$P_{D}$	Power Dissipation	(Note 1b)	1.0	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +150	°C

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	(Note 1)	25	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	125	

#### **Package Marking and Ordering Information**

Device Marking	Device	Reel Size	Tape Width	Quantity
FDS8817NZ	FDS8817NZ	13"	12mm	2500 units

# **Electrical Characteristics** $T_J = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units	
Off Chara	Off Characteristics						
$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30			V	
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , referenced to 25°C		20		mV/°C	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 24V,  V_{GS} = 0V$			1	μΑ	
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20V, \ V_{DS} = 0V$			±10	μΑ	

#### On Characteristics (Note 2)

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1	1.8	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , referenced to 25°C		-6		mV/°C
		$V_{GS} = 10V, I_D = 15A$		5.4	7	
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 4.5V, I_D = 12.6A$		7.0	10	mΩ
		$V_{GS} = 10V, I_D = 15A T_J = 125^{\circ}C$		7.5	11	
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 5V, I_{D} = 15A$		54		S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 45V V 0V	1805	2400	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 15V, V_{GS} = 0V,$ f = 1MHz	335	445	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 11/11/12	200	300	pF
$R_g$	Gate Resistance	f = 1MHz	1.4		Ω

### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time				11	22	ns
t <sub>r</sub>	Rise Time	$V_{DD} = 15V, I_D = 15V$	$V_{DD} = 15V, I_{D} = 15A$ $V_{GS} = 10V, R_{GEN} = 6\Omega$		13	26	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>GS</sub> = 10V, K <sub>GEN</sub>			25	40	ns
t <sub>f</sub>	Fall Time				7	14	ns
$Q_g$	Total Gate Charge	$V_{GS} = 0V \text{ to } 10V$	$V_{DD} = 15V$		32	45	nC
Qg	Total Gate Charge	$V_{GS} = 0V \text{ to } 5V$	I <sub>D</sub> = 15A		17	24	nC
Q <sub>gs</sub>	Gate to Source Charge		_		6		nC
$Q_{gd}$	Gate to Drain "Miller" Charge				7		nC

#### **Drain-Source Diode Characteristics**

$V_{SD}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_S = 2.1A$ (Note 2)		8.0	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	L = 15A di/dt = 100A/vo		24	36	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$I_F = 15A$ , $di/dt = 100A/\mu s$		15	23	nC

Notes:

1. R<sub>BJA</sub> is the sum of the junction-to-case and case-to- ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta JA}$  is determined by the user's board design.



a) 50°C/W when mounted on a 1in<sup>2</sup> pad of 2 oz copper.



b) 125°C/W when mounted on a minimum pad .

- Pulse Test: Pulse Width < 300 us, Duty Cycle < 2%.</li>
   The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.
   Starting T<sub>J</sub> = 25°C, L = 3mH, I<sub>AS</sub> = 11A, V<sub>DD</sub> = 30V, V<sub>GS</sub> = 10V.

### Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

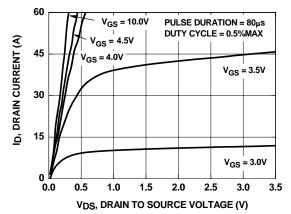


Figure 1. On-Region Characteristics

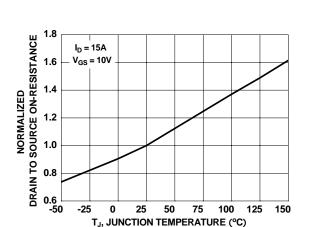


Figure 3. Normalized On-Resistance vs Junction Temperature

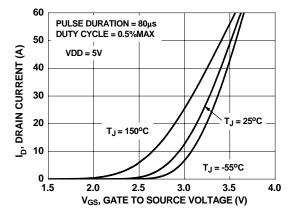


Figure 5. Transfer Characteristics

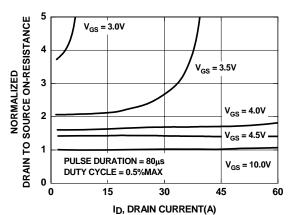


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

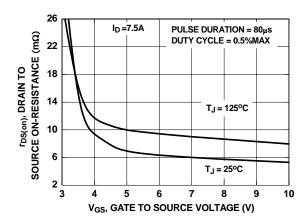


Figure 4. On-Resistance vs Gate to Source Voltage

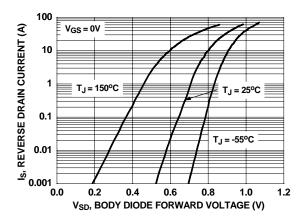


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# Typical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

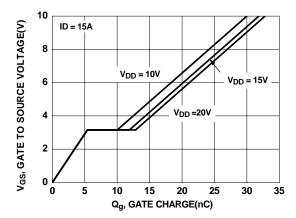


Figure 7. Gate Charge Characteristics

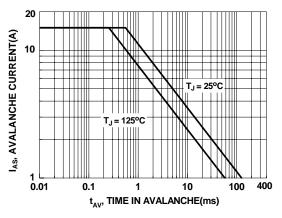


Figure 9. Unclamped Inductive Switching Capability

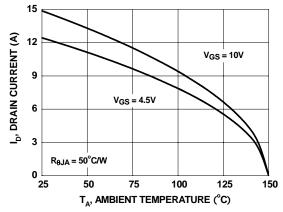


Figure 11. Maximum Continuous Drain Current vs Ambient Temperature

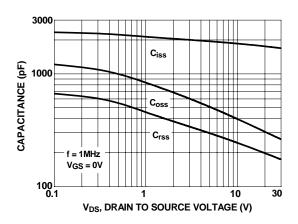


Figure 8. Capacitance vs Drain to Source Voltage

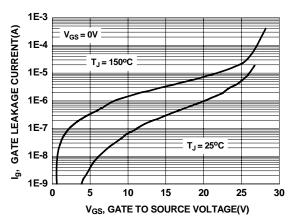


Figure 10. Gate Leakage Current vs Gate to Source Voltage

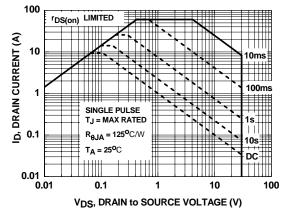


Figure 12. Forward Bias Safe
Operating Area

# **Typical Characteristics** T<sub>J</sub> = 25°C unless otherwise noted

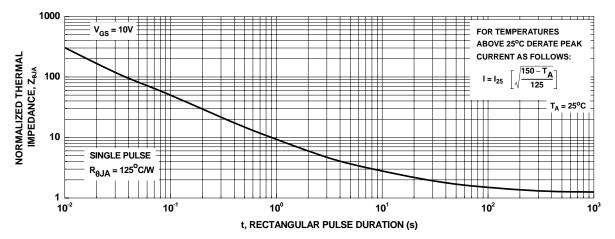


Figure 13. Single Pulse Maximum Power Dissipation

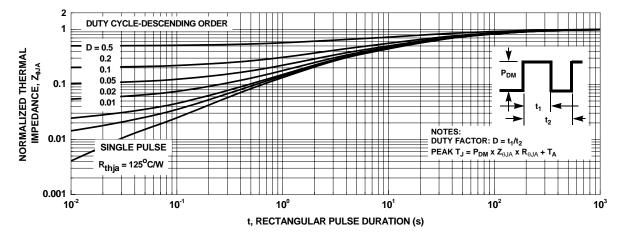


Figure 14. Transient Thermal Response Curve





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